Type	L #	Hits	Search Text	DBs	Time Stamp
BRS	L1	286	((determin$5 or detect$5 or measur$5 or inspect$5 or monitor$5 or calculat$5 or identif$5) near5 (foreign near2 particle)) and @ad<=19911017	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 14:05
BRS	L2	35	(pitch near2 variable) near4 filter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 09:46
BRS	L3	0	1 and 2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 09:46
BRS	L4	2600	pitch near4 filter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 09:46
BRS	L5	0	1 and 4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 09:46
BRS	L6	9001	spatial near2 filter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 09:47
BRS	L7	9	1 and 6	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 11:42
BRS	L8	141	variable near3 (spatial near2 filter)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 13:22
BRS	L9	1779	(((determin$5 or detect$5 or measur$5 or inspect$5 or identif$6) near4 (defect$2 or foreign)) with surface) same wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 13:29
BRS	L10	3001	(((determin$5 or detect$5 or measur$5 or inspect$5 or identif$6) near4 (defect$2 or foreign)) with surface) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 13:29
BRS	L11	0	9 and 8 and @ad<=19911017	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 14:07
BRS	L12	1	10 and 8 and @ad<=19911017	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 14:07
BRS	L13	58	pitch near5 (spatial near2 filter)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 14:14
BRS	L14	0	1 and 13	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 14:14
BRS	L15	3088	pitch near5 filter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 14:14
BRS	L16	0	1 and 15	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/08 14:14